Notice of References Cited

Application/Control No. 10/722,934	Applicant(s)/F Reexamination LANE ET AL.	
Examiner	Art Unit	
Alexander O Williams	2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0197856 A1	12-2002	Matsuse et al.	438/652
	В	US-2002/0102826 A1	08-2002	Shimamoto et al.	438/575
	C	US-6,740,252 B2	05-2004	Kraus et al.	252/79.1
	D	US-2002/0036348 A1	03-2002	Matsunaga et al.	257/758
	E	US-2002/0123235 A1	09-2002	Kraus et al.	438/755
	F	US-5,637,533	06-1997	Choi, Kyeong K.	438/643
	G	US-2004/0113279 A1	06-2004	Chen et al.	257/774
	Н	US-2004/0152255 A1	08-2004	Seidl et al.	438/240
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				X 18 10 10 10 10 10 10 10 10 10 10 10 10 10	
	Р					
	O					
	R					
	S					
	Т				*	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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